

# 16K (2K×8) UV ERASABLE PROM

- FAST ACCESS TIME: 350ns MAX M2716-1 450ns MAX M2716
- SINGLE +5V POWER SUPPLY
- LOW POWER DISSIPATION:
   525 mW MAX. ACTIVE POWER
   132 mW MAX. STANDBY POWER
- SIMPLE PROGRAMMING REQUIREMENTS
   — SINGLE LOCATION PROGRAMMING
  - PROGRAMS WITH ONE 50 ms PULSE
- INPUTS AND OUTPUTS TTL COMPATIBLE DURING READ PROGRAM
- COMPLETELY STATIC
- EXTENDED TEMPERATURE RANGE



Ceramic Package

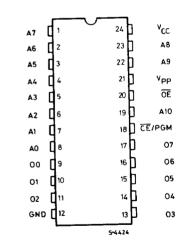
ORDERING NUMBERS: M2716F1 M2716-1F1 M2716F6 M2716-1F6

DESCRIPTION The M2716 is a 16.384-bit ultraviolet erasable and electrically programmable read-only memory (EPROM). The M2716 operates from a single -5V power supply, has a static standby mode, and features fast single address location programming. It makes designing with EPROMs faster, easier and more economical. The M2716, with its single 5-volt supply and with an access time up to 350ns, is ideal for use with the newer high performance +5V microprocessor such as the Z8®, Z80® Z8000TM. The M2716P is also the first EPROM with a static standby mode which reduces the power dissipation without increasing access time. The maximum active power dissipation is 525 mW while the maximum standby power dissipation is only 132 mW, a 75% savings.

The M2716 has the simplest and fastest method yet devised for programming EPROMs — single pulse TTL level programming. No need for high voltage pulsing because all programming controls are handled by TTL signals. Program any location at any time-either individually, sequentially or at random, with the M2716's single address location programming. Total programming time for all 16.384 bits is only 100 seconds:

The M2716 is available in 24-lead dual in-line ceramic package glass lens (frit-seal)

## PIN CONNECTIONS

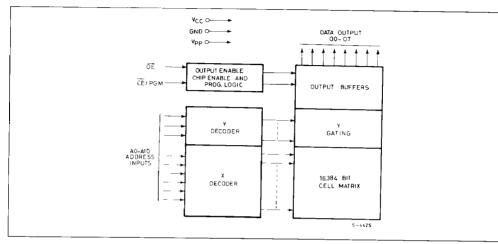


#### PIN NAMES

A0-A10	ADDRESSES	
CE/PGM	CHIP ENABLE/PROGRAM	
ŌĒ	OUTPUT ENABLE	
00-07	OUTPUTS	

## M2716

## **BLOCK DIAGRAM**



## **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
VI	All Input or Output voltages with respect to ground	+ 6 to - 0.3	V
V <sub>PP</sub>	Supply voltage with respect to ground during program	+26.5 to - 0.3	
T <sub>amb</sub>	Ambient temperature under bias: standard extended	0 to + 70 -40 to + 85	°C
T <sub>stg</sub>	Storage temperature range	-65 to +125	°C

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## **OPERATING MODES**

PINS	CE/PGM	OE	Vpp	V <sub>CC</sub> (24)	OUTPUTS
MODE	(18)	(20)	(21)	(24)	(9-11, 13-17)
READ	V <sub>IL</sub>	V <sub>IL</sub>	+ 5	+5	D <sub>OUT</sub>
STANDBY	V <sub>IH</sub>	Don't Care	+ 5	+5	HIGH Z
PROGRAM	Pulse V <sub>IL</sub> to V <sub>IH</sub>	V <sub>IH</sub>	+ 25	+5	D <sub>IN</sub>
PROGRAM VERIFY	$V_{IL}$	V <sub>IL</sub>	+ 25	+5	D <sub>OUT</sub>
PROGRAM INHIBIT	V <sub>IL</sub>	V <sub>IH</sub>	+ 25	+5	HIGH Z

Note: The five modes of operation of the M2716P are listed in this table. It should be noted that all inputs for the five modes are at TTL levels. The power supplies required are a  $+5V\ V_{CC}$  and a Vpp power supply must be at 25V during the three programming modes, and must be at 5V in the other two modes.

## **READ OPERATION**

DC AND AC OPERATING CONDITIONS

M2716F1	M2716-1F1	M2716F6	M2716-1F6
0 to 70°C	0 to 70°C	−40 to 85°C	− 40 to 85°C
5V ±5%	5V ±10%	5V ±5%	5V ±10%
V <sub>CC</sub> ± 0.6	V <sub>CC</sub> ± 0.6	V <sub>CC</sub> ± 0.6	V <sub>CC</sub> ± 0.6
	M2716F1 0 to 70°C 5V ±5%	M2716F1         M2716-1F1           0 to 70°C         0 to 70°C           5V ±5%         5V ±10%	M2716F1         M2716-1F1         M2716F6           0 to 70°C         0 to 70°C         −40 to 85°C           5V ±5%         5V ±10%         5V ±5%

## DC AND OPERATING CHARACTERISTICS

	Parameter					
Symbol		Test Conditions	Min.	Typ. (3)	Max.	Unit
	Input Load Current	V <sub>I</sub> = 5.25V			10	μA
<u>'Ll</u>	Output Leakage Current	V <sub>O</sub> = 5.25V			10	μA
lpp1(2)	V <sub>PP</sub> = 5.25V				5	mA
ICC1(2)	V <sub>CC</sub> Supply Current (Standby)	$\overline{CE} = V_{1H} \overline{OE} = V_{1L}$		10	25	mA
ICC2(2)	V <sub>CC</sub> Supply Current (Active)	OE = CE = V <sub>IL</sub>	L	57	100	mA
VIL	Input Low Voltage		-0.1		0.8	V.
VIH	Input High Voltage		2.0		V <sub>CC</sub> + 1	V
VOL	Output Low Voltage	I <sub>OL</sub> = 2.1 mA			0.45	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4			V

## AC CHARACTERISTICS

		Test	M2716		M2716-1		
Symbol	Parameter	Conditions	Min	Max	Min	Max	Unit
tACC	Address to Output Delay	CE = OE = V <sub>IL</sub>		450		350	ns
tCE	CE to Output Delay	OE = V <sub>IL</sub>		450		350	ns
toe	OE to Output Delay	CE = V <sub>IL</sub>		120		120	ns
t <sub>DF(4)</sub>	OE High to Output Float	CE = V <sub>IL</sub>	0	100	0	100	ns
t <sub>OH</sub>	Output Hold from Address CE or OE Whichever Occurred First	CE = OE = V <sub>IL</sub>	0		0		ns

## CAPACITANCE(4) (Tamb = 25°C, f = 1 MHz)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
	Input Capacitance	V <sub>1</sub> = 0V		4	6	pF
	Output Capacitance	V <sub>O</sub> = 0V	L	8	12	pF

- V<sub>CC</sub> must be applied simultaneously or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.
   V<sub>PP</sub> may be connected directly to V<sub>CC</sub> except during programming.
  The supply current would then be the sum of I<sub>CC</sub> and I<sub>PP1</sub>.
   Typical values are for T<sub>amb</sub> = 25°C and nominal supply voltages.
   This parameter is only sampled and not 100% tested.

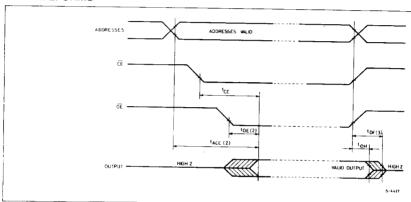
#### AC TEST CONDITIONS

Output Load: 100pF + 1TTL Gate Input Rise and Fall Times: ≤ = 20ns Input Pulse Levels: 0.8 to 2.2V

Timing Measurement Reference Levels: Inputs 1 and 2V

Outputs 0.8 and 2V

#### AC WAVEFORMS



#### Notes:

- V<sub>CC</sub> must be applied simultaneously or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.
- $\overline{\text{OE}}$  may be delayed up to  $t_{ACC}$   $t_{DE}$  after the falling edge  $\overline{\text{CE}}$  without impact on  $t_{ACC}$ - $t_{DE}$  is specified from  $\overline{\text{OE}}$  or  $\overline{\text{CE}}$  whichever occurs first.

#### READ MODE

The M2716 has two control functions, both of which must be logically satisfied in order to obtain data at the outputs. Chip Enable (CE) is the power control and should be used for device selection. Output Enable (OE) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (tACC) is equal to the delay from CE to output (tCE). Data is available at the outputs 120 ns ( $t_{OE}$ ) after the falling edge of  $\overline{OE}$ , assuming that  $\overline{CE}$  has been low and addresses have been stable for at least tACC-tOE.

#### STANDBY MODE

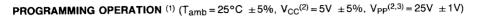
The M2716 has a standby mode which reduces the active power dissipation by 75%, from 525mW to 132mW. The M2716 is placed in the standby mode by applying a TTL high signal to CE input. When in standby mode, the output are in a high impedance state, independent of the OE input.

## OUTPUT OR-TIEING

Because M2716's are usually used in larger memory arrays, the product has 2 line control function that accommodates this use of multiple memory connection. The two line control function allows for:

- a) the lowest possible memory power dissipation
- b) complete assurance that output bus contention will not ouccur.

To most efficiently use these two control lines, it is recommended that  $\overline{\text{CE}}$  be decoded and used as the primary device selecting function, while OE (pin 20) be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low power standby mode and the output pins are only active when data is desired from a particular memory device.



## DC AND OPERATING CHARACTERISTIC:

Symbol	Parameter	Test Conditions		Unit		
			Min.	Тур.	Max.	Onn
ւլլ	Input Current (for Any Input)	V <sub>I</sub> = 5.25V/0.45			10	μΑ
V <sub>IL</sub>	Input Low Level		-0.1		0.8	V
V <sub>IH</sub>	Input High Level		2.0		V <sub>CC</sub> +1	V
Icc	V <sub>CC</sub> Supply Current				100	mA
l <sub>PP1</sub>	V <sub>PP</sub> Supply Current	CE/PGM = V <sub>IL</sub>			5	mA
lpp2	V <sub>PP</sub> Supply Current During Programming Pulse	CE/PGM =V <sub>IH</sub>			30	mA

## AC CHARACTERISTICS

		Test Conditions				
Symbol	Parameter		Min.	Тур.	Max.	Unit
tas	Address Setup Time		2			μS
toes	OE Setup Time		2			μS
t <sub>DS</sub>	Data Setup Time		2			μS
t <sub>AH</sub>	Address Hold Time		2			μS
toeh	OE Hold Time		2			μS
t <sub>DH</sub>	Data Hold Time		2			μS
t <sub>DF</sub>	Output Enable to Output Float Delay	$\overline{OE}/PGM = V_{IL}$	0		120	ns
toE	Output Enable to Output Delay	CE/PGM = VIL			120	νS
tpw	Program Pulse Width		45	50	55	ms
t <sub>PRT</sub>	Program Pulse Rise Time		5			ns
t <sub>PFT</sub>	Program Pulse Fall Time		5			νS

CAUTION: The VCC and Vpp supplied must be sequenced on and off such that VCC is applied simultaneosly or before Vpp and removed simultaneosly or after Vpp to prevent damage to the M2716. The maximum allowable voltage during programming which may be applied to the VPP with respect to ground is +26V. Care must be taken when switching the VPP supply to prevent overshoot exceeding the 26-volt maximum specification. For convenience in programming, the M2716 may be verified with the Vpp supply at 25V ± 1V. During normal read operation, however, Vpp must be at Vcc.

## Notes:

SGS guarantees the product only if it is programmed to specifications described herein.

V<sub>CC</sub> must be applied simultaneously or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>. The M2716 must not be inserted into or removed from a board with V<sub>PP</sub> at 25 ± 1V to prevent damage to the device

The maximum allowable voltage which may be applied to the V<sub>PP</sub> pin during programming is + 26V. Care must be taken when switching the V<sub>PP</sub> supply to prevent overshoot exceeding this 26V maximum specification.

## AC TEST CONDITIONS

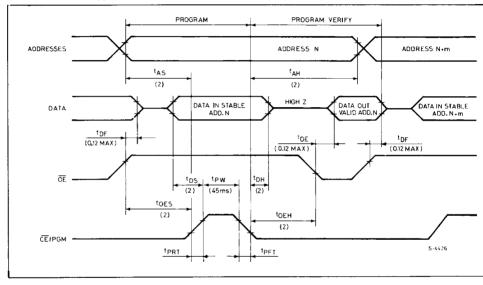
 $V_{CC} = 5V \pm 5\%$  $V_{PP} = 25V \pm 1V$ 

Input Rise and Fall Times (10% to 90%) = 20 ns

Input Pulse Levels = 0.8V to 2.2V Input Timing Reference Level = 1V and 2V Output Timing Reference Level = 0.8V and 3

### PROGRAMMING WAVEFORMS

 $(V_{PP} = 25V \pm 1V, V_{CC} = 5V \pm 5\%)$ 



Note: All times shown in parentheses are minimum times and are µsec unless otherwise noted

#### PROGRAMMING

Initially, and after each erasure, all bits of the M2716 are in the "1" state. Data is introduced by selectively programming "0's" into the desired bit locations. Although only "0's" will be programmed, both "1's" and "0's" can be presented in the data word. The only way to change a "0" to a "1" is by ultraviolet light erasure. The M2716 is in the programming mode when the VPP power supply is at 25V and OE is at VIH. The data to be programmed is applied 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL. When the address and data are stable, a 50 msec, active high, TTL program pulse is applied to the CE/PGM input. A program pulse must be applied at each address location to be programmed You can program any location at any time - either individually, sequentially, or at random. The program pulse has a maximum width of 55 msec. The M2716 must not be programmed a DC signal applied to the CE/PGM input. Programming of multiple M2716s in parallel with the same data can be easily accomplished due the simplicity of the programming requiremental Like inputs of the paralleled M2716s may be concerted together when they are programmed with same data. A high level TTL pulse applied the CE/PGM input-programs the parallel M271

## PROGRAM INHIBIT

Programming of multiple M2716s in parallel with different data is also easily accomplished. Exc for CE/PGM, all like inputs (including OE) of parallel M2716s may be common. A TTL level gram pulse applied to a M2716's CE/PGM in with V<sub>PP</sub> at 25V will program that M2716. A level CE/PGM input inhibits the other M2716 for beign programmed.

#### PROGRAM VERIFY

A verify should be performed on the programmed bits to determine that they were correctly programmed. The verify may be performed with  $V_{PP}$  at 25V. Except during programming and program verify,  $V_{PP}$  must be at 5V.

## **ERASURE OPERATION**

The erasure characteristics of the M2716 are such that erasure begins to occur when exposed to light with wavelengths shorter than approximately 4000 Angstroms (A). It should be noted that sunlight and certain types of fluorescent lamps have wavelengths in the 3000-4000 A range. Data show that constant exposure to room level fluorescent lighting could erase the typical M2716 in approximately 3 years, while it would take approximately

1 week to cause erasure when exposed to direct sunlight. If the M2716 is to be exposed to these types of lighting conditions for extended periods of time, it is suggested to put opaque labels over the M2716 window to prevent unintentional erasure.

The recommended erasure procedure for the M2716 is exposure to shortware ultraviolet light which has a wavelength of 2537 Angstroms (A). The integrated dose (i.e. UV intensity X exposure time) for erasure should be a minimum of 15 W-sec/cm². The erasure time with this dosage is approximately 15 to 20 minutes using an ultraviolet lamp with a 12000  $\mu$  W/cm² power rating. The M2716 should be placed within 2.5 cm of the lamp tubes during erasure. Some lamps have a filter on their tubes which should be removed before erasure.